

Thermal stability of W/Mo JET divertor coatings on CFC substrate

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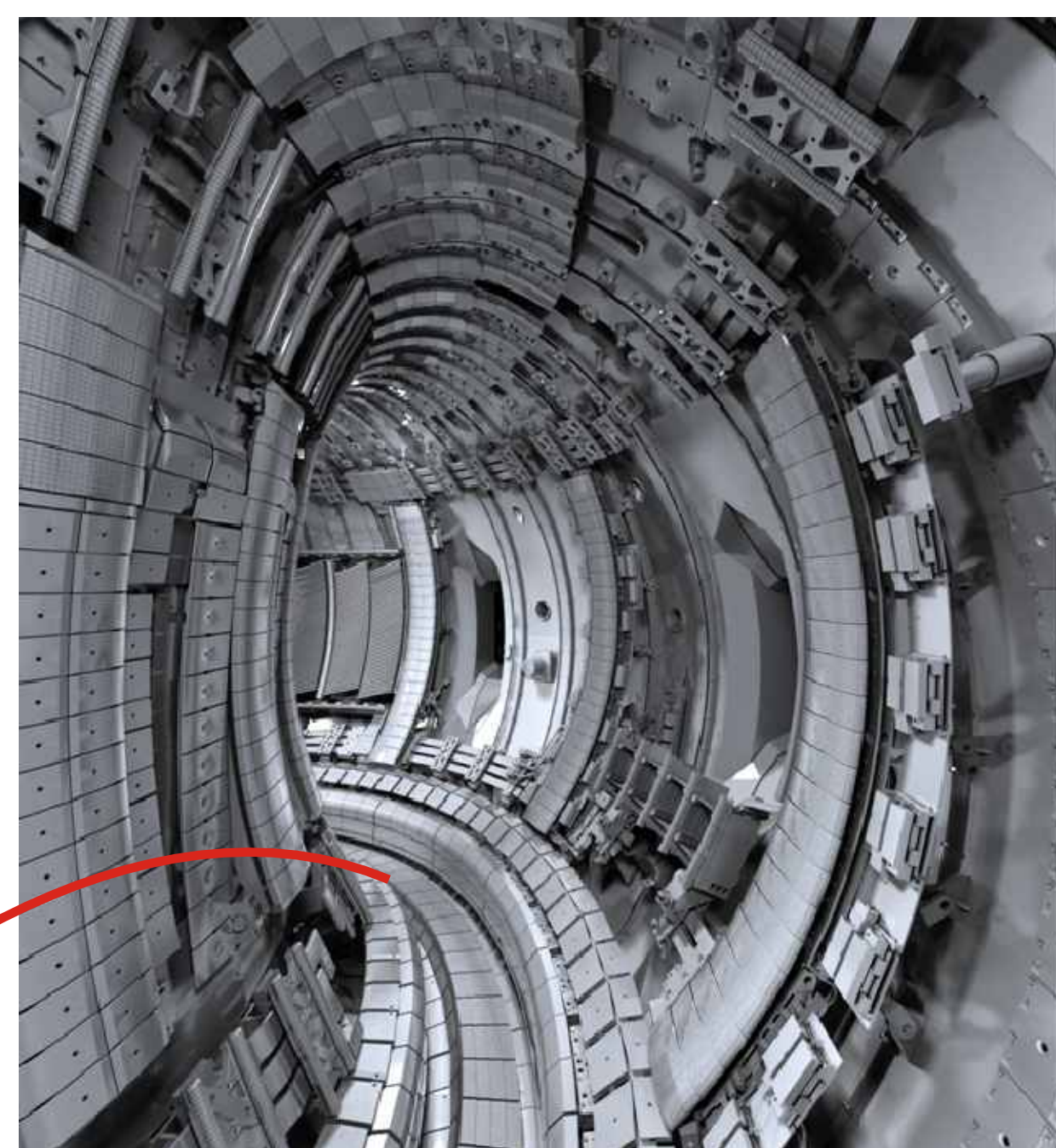
Introduction

The JET reactor first wall material in the ITER-like wall project:

- Beryllium
- Carbon
- Tungsten

In the bottom part of the inside of the reactor - **divertor**

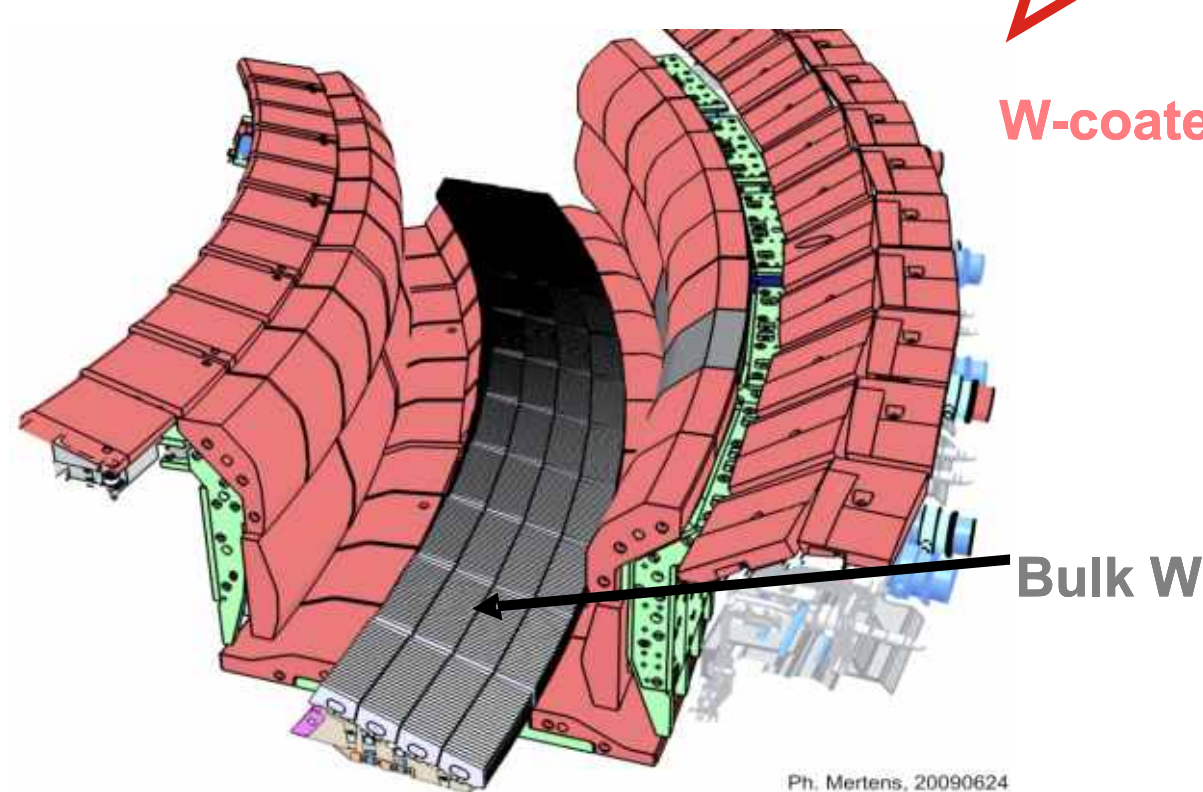
Divertor made of full carbon tiles together with **carbon tiles coated with tungsten**.



The inside of the JET reactor

W-coated CFC

During the operation of the reactor, diffusion of carbon from the substrate to the W layers is expected. Due to the fact that tungsten easily form carbides, brittle carbide phases may be created at the interface, strongly affecting the thermo-mechanical performance of the coatings. For the prediction of the operation time of such coated tiles, carbon diffusion and carbide formation need to be determined.

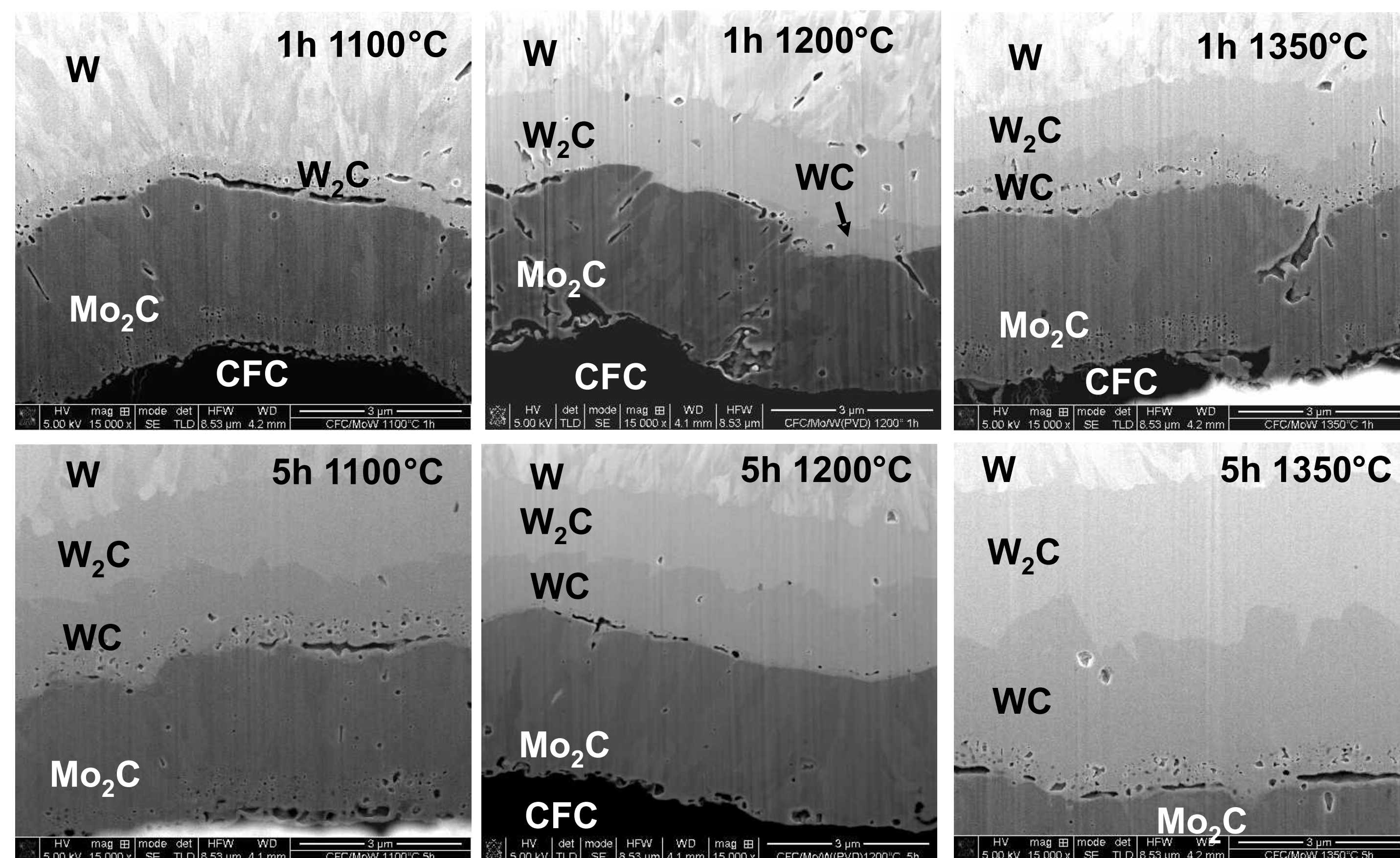


Scheme of the divertor section in JET

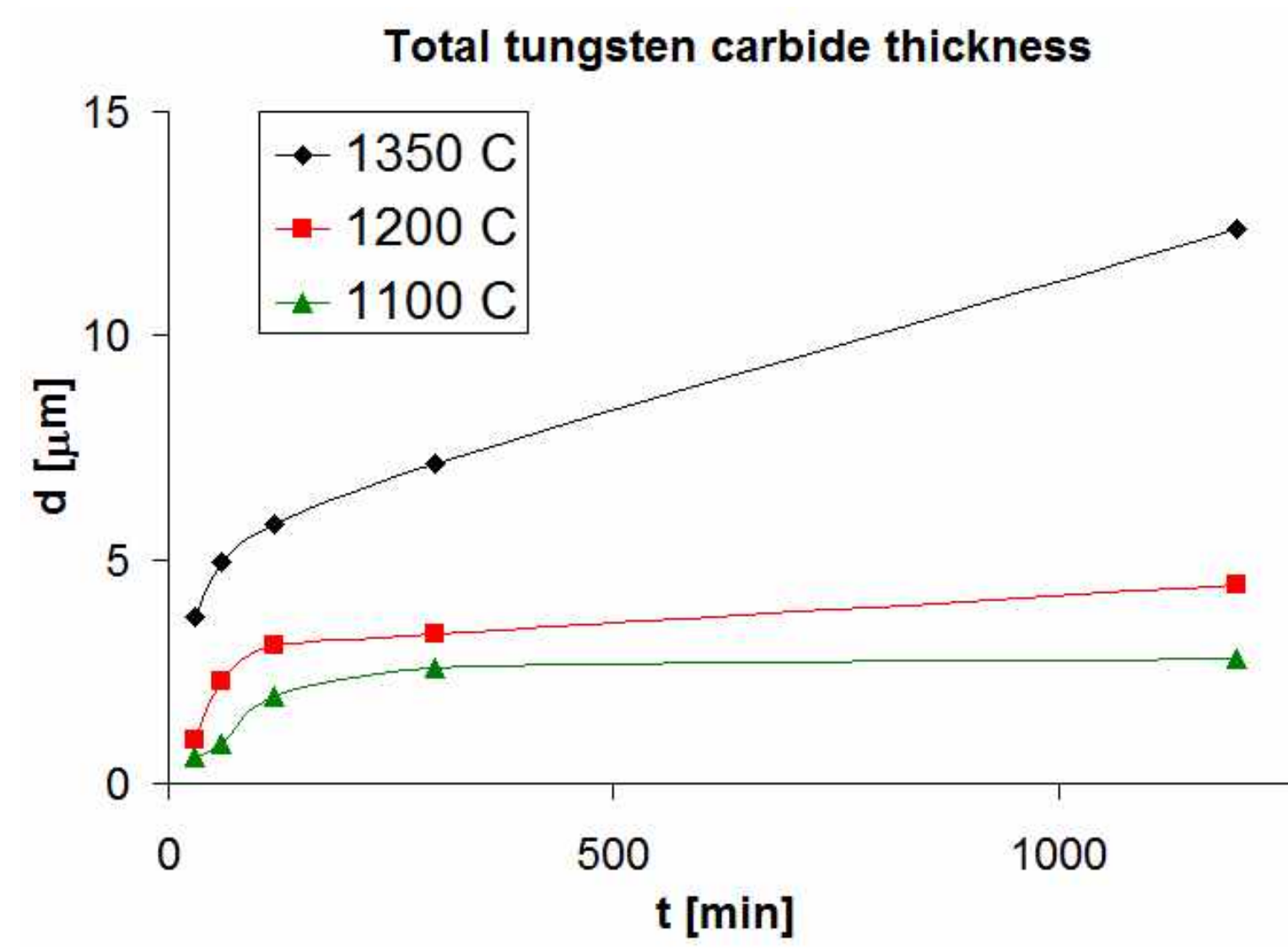
Graph: Ph. Mertens, FZJ

Ph. Mertens, 20090624

Results



SEM images of FIB prepared cross-section of samples annealed at 1100°C, 1200°C and 1350°C

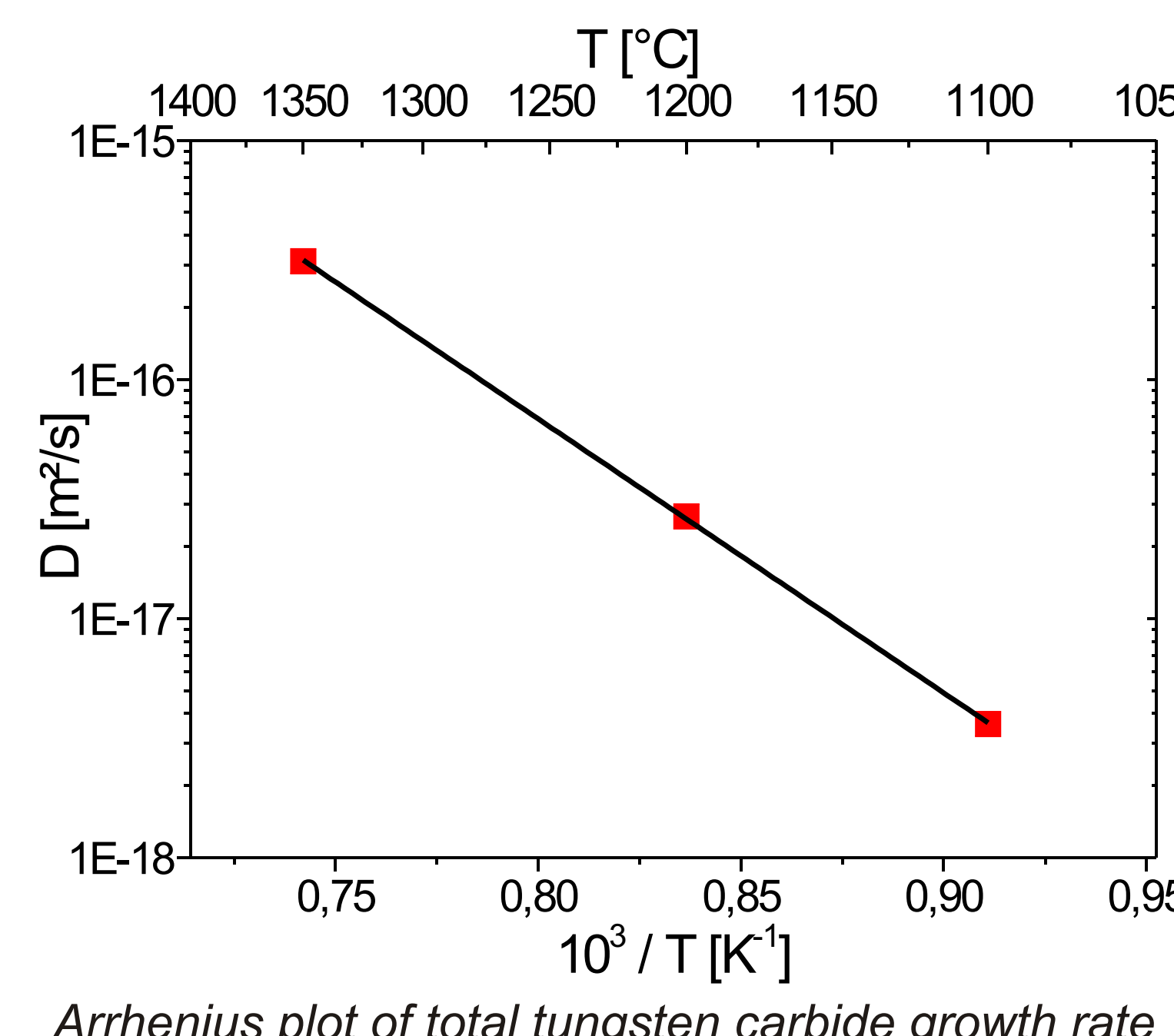
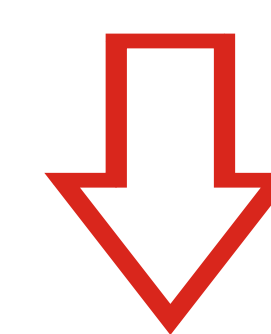


Total thickness of tungsten carbide versus growth time

TEM diffraction analysis enabled **Mo₂C** carbide identification in the initial molybdenum layer and two tungsten carbide phases - **WC** and **W₂C** in the initial tungsten layer after subsequent annealing.

SEM cross section investigation => average thickness of total tungsten carbide thickness measured and plotted versus growth time.

Growth of the total carbide thickness (W₂C phase) follow the parabolic law.



Arrhenius plot of total tungsten carbide growth rate

Assumption:

Movement of W₂C reaction front can be described by one single diffusion process, i.e.

$$d^2 = 6Dt$$

with a "diffusion coefficient" D.

Arrhenius plot of the "diffusion coefficient" versus annealing temperature =>

In the investigated temperature window the process can be described by one single "effective" activation energy:

$$E_A = 3.4 \text{ eV}$$

Experiment

Material production:

Full divertor tiles with 3-4 μm Mo and 10 - 25 μm W layer deposited on CFC substrate by combined magnetron sputtering and ion implantation technology (CMSII).

Machining of samples with dimension 10 x 10 x 3 mm for further heat treatment analysis

Annealing:

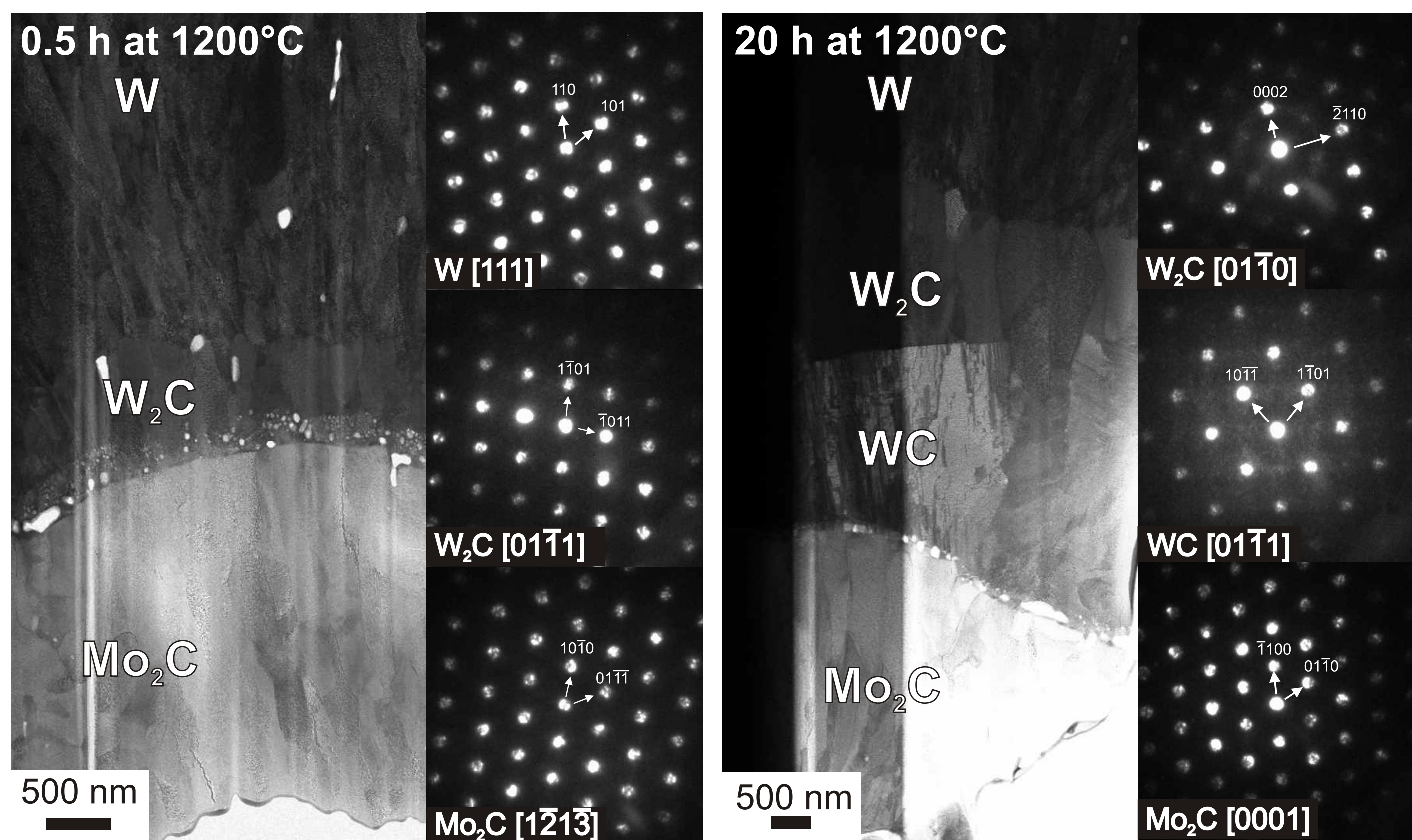
Ar flow/vacuum furnace at 1100°C, 1200°C, 1350°C for 0.5h, 1h, 2h, 5h, 20h

Electron microscopy observation:

Carbon diffusion measurement - Dual Beam FIB/SEM device: => FIB cross-section preparation => SEM observation

Phase determination => thin lamella preparation by single beam FIB device => TEM observation => local convergent beam diffraction analysis

Results - TEM analysis



TEM images with diffraction analysis of multilayer systems after 0.5h and 20h annealing at 1200°C

Conclusion

TEM diffraction analysis => **Mo₂C** carbide as well as **W₂C** and **WC** carbide identified.

Growth of the W₂C carbide phase follow the parabolic law => main process controlling the growth is carbon diffusion from the substrate to the reaction front.

Activation energy E_A can be employed to model the kinetics of the carbide layer growth for complex temperature-time history

=> **Lifetime assessment of the coatings during JET operation**